

54ABT241

Octal Buffer/Line Driver with TRI-STATE® Outputs

General Description

The ABT241 is an octal buffer and line driver with 3-STATE outputs designed to be employed as a memory and address driver, clock driver, or bus-oriented transmitter/receiver.

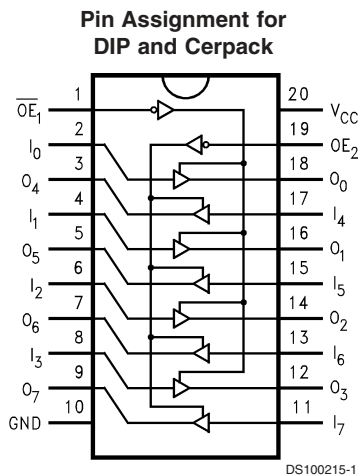
Features

- Non-inverting buffers
- Output sink capability of 48 mA, source capability of 24 mA
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Nondestructive hot insertion capability
- Standard Microcircuit Drawing (SMD) 5962-9322701

Ordering Code

| Military | Package Number | Package Description |
|---------------|----------------|---|
| 54ABT241J-QML | J20A | 20-Lead Ceramic Dual-In-Line |
| 54ABT241W-QML | W20A | 20-Lead Cerpack |
| 54ABT241E-QML | E20A | 20-Lead Ceramic Leadless Chip Carrier, Type C |

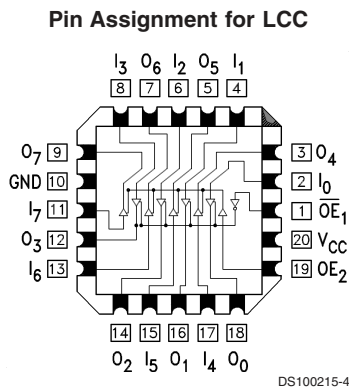
Connection Diagram



| Pin Names | Description |
|-------------------|-----------------------------------|
| \overline{OE}_1 | Output Enable Input (Active Low) |
| OE_2 | Output Enable Input (Active High) |
| I_0-I_7 | Inputs |
| O_0-O_7 | Outputs |

| \overline{OE}_1 | I_{0-3} | O_{0-3} | \overline{OE}_2 | I_{4-7} | O_{4-7} |
|-------------------|-----------|-----------|-------------------|-----------|-----------|
| H | X | Z | L | X | Z |
| L | H | H | H | H | H |
| L | L | L | H | L | L |

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Immaterial
 Z = High Impedance



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Absolute Maximum Ratings (Note 1)

| | |
|--|--------------------------------------|
| Storage Temperature | -65°C to +150°C |
| Ambient Temperature under Bias | -55°C to +125°C |
| Junction Temperature under Bias | |
| Ceramic | -55°C to +175°C |
| V _{CC} Pin Potential to Ground Pin | -0.5V to +7.0V |
| Input Voltage (Note 2) | -0.5V to +7.0V |
| Input Current (Note 2) | -30 mA to +5.0 mA |
| Voltage Applied to Any Output in the Disabled or Power-Off State | -0.5V to 5.5V |
| in the HIGH State | -0.5V to V _{CC} |
| Current Applied to Output in LOW State (Max) | twice the rated I _{OL} (mA) |

| | |
|---|---------|
| DC Latchup Source Current (Over Comm Operating Range) | -500 mA |
| Over Voltage Latchup (I/O) | 10V |

Recommended Operating Conditions

| | |
|------------------------------|-----------------|
| Free Air Ambient Temperature | |
| Military | -55°C to +125°C |
| Supply Voltage | |
| Military | +4.5V to +5.5V |
| Minimum Input Edge Rate | (ΔV/Δt) |
| Data Input | 50 mV/ns |
| Enable Input | 20 mV/ns |

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

DC Electrical Characteristics

| Symbol | Parameter | Min | Typ | Max | Units | V _{CC} | Conditions |
|------------------|-----------------------------------|-----------------|-----|------|------------|-----------------|---|
| V _{IH} | Input HIGH Voltage | 2.0 | | | V | | Recognized HIGH Signal |
| V _{IL} | Input LOW Voltage | | | 0.8 | V | | Recognized LOW Signal |
| V _{CD} | Input Clamp Diode Voltage | | | -1.2 | V | Min | I _{IN} = -18 mA |
| V _{OH} | Output HIGH Voltage | 54ABT | 2.5 | | V | Min | I _{OH} = -3 mA |
| | | 54ABT | 2.0 | | V | Min | I _{OH} = -24 mA |
| V _{OL} | Output LOW Voltage | 54ABT | | 0.55 | V | Min | I _{OL} = 48 mA |
| I _{IH} | Input HIGH Current | | | 5 | μA | Max | V _{IN} = 2.7V (Note 4) |
| | | | | 5 | μA | Max | V _{IN} = V _{CC} |
| I _{BVI} | Input HIGH Current Breakdown Test | | | 7 | μA | Max | V _{IN} = 7.0V |
| I _{IL} | Input LOW Current | | | -5 | μA | Max | V _{IN} = 0.5V (Note 4) |
| | | | | -5 | μA | Max | V _{IN} = 0.0V |
| V _{ID} | Input Leakage Test | 4.75 | | | V | 0.0 | I _{ID} = 1.9 μA All Other Pins Grounded |
| I _{OZH} | Output Leakage Current | | | 50 | μA | 0 - 5.5V | V _{OUT} = 2.7V; $\overline{OE}_n = 2.0V$ |
| I _{OZL} | Output Leakage Current | | | -50 | μA | 0 - 5.5V | V _{OUT} = 0.5V; $\overline{OE}_n = 2.0V$ |
| I _{OS} | Output Short-Circuit Current | -100 | | -275 | mA | Max | V _{OUT} = 0.0V |
| I _{CEx} | Output High Leakage Current | | | 50 | μA | Max | V _{OUT} = V _{CC} |
| I _{ZZ} | Bus Drainage Test | | | 100 | μA | 0.0 | V _{OUT} = 5.5V; All Others GND |
| I _{CCH} | Power Supply Current | | | 50 | μA | Max | All Outputs HIGH |
| I _{CCL} | Power Supply Current | | | 30 | mA | Max | All Outputs LOW |
| I _{CCZ} | Power Supply Current | | | 50 | μA | Max | $\overline{OE}_n = V_{CC}$; All Others at V _{CC} or Ground |
| I _{CCT} | Additional I _{CC} /Input | Outputs Enabled | | 2.5 | mA | Max | V _I = V _{CC} - 2.1V |
| | | Outputs 3-STATE | | 2.5 | mA | Max | Enable Input V _I = V _{CC} - 2.1V |
| | | Outputs 3-STATE | | 50 | μA | Max | Data Input V _I = V _{CC} - 2.1V All Others at V _{CC} or Ground |
| I _{CCD} | Dynamic I _{CC} (Note 4) | No Load | | 0.1 | mA/ MHz | Max | Outputs Open $\overline{OE}_n = GND$, (Note 3) One Bit Toggling, 50% Duty Cycle |

Note 3: For 8 bits toggling, I_{CCD} < 0.8 mA/MHz.

Note 4: Guaranteed, but not tested.

DC Electrical Characteristics

| Symbol | Parameter | Min | Max | Units | V _{CC} | Conditions C _L = 50 pF, R _L = 500Ω |
|------------------|--|-----|-------|-------|-----------------|--|
| V _{OLP} | Quiet Output Maximum Dynamic V _{OL} | | 0.67 | V | 5.0 | T _A = 25°C (Note 5) |
| V _{OLV} | Quiet Output Minimum Dynamic V _{OL} | | -1.35 | V | 5.0 | T _A = 25°C (Note 5) |

Note 5: Max number of outputs defined as (n). n – 1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

AC Electrical Characteristics

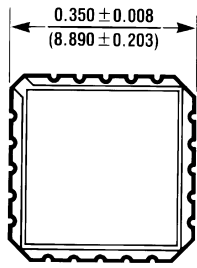
| Symbol | Parameter | T _A = –55°C to +125°C V _{CC} = 4.5V–5.5V C _L = 50 pF | | Units |
|------------------|-------------------|---|-----|-------|
| | | Min | Max | |
| t _{PLH} | Propagation Delay | 0.8 | 5.3 | ns |
| t _{PHL} | Data to Outputs | 0.8 | 5.0 | |
| t _{PZH} | Output Enable | 1.0 | 7.0 | ns |
| t _{PZL} | Time | 1.0 | 7.0 | |
| t _{PHZ} | Output Disable | 0.8 | 7.9 | ns |
| t _{PLZ} | Time | 0.8 | 6.2 | |

Capacitance

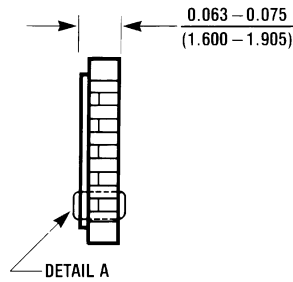
| Symbol | Parameter | Typ | Units | Conditions T _A = 25°C |
|---------------------------|--------------------|-----|-------|-------------------------------------|
| C _{IN} | Input Capacitance | 5.0 | pF | V _{CC} = 0V |
| C _{OUT} (Note 6) | Output Capacitance | 9.0 | pF | V _{CC} = 5.0V |

Note 6: C_{OUT} is measured at frequency f = 1 MHz, per MIL-STD-883B, Method 3012.

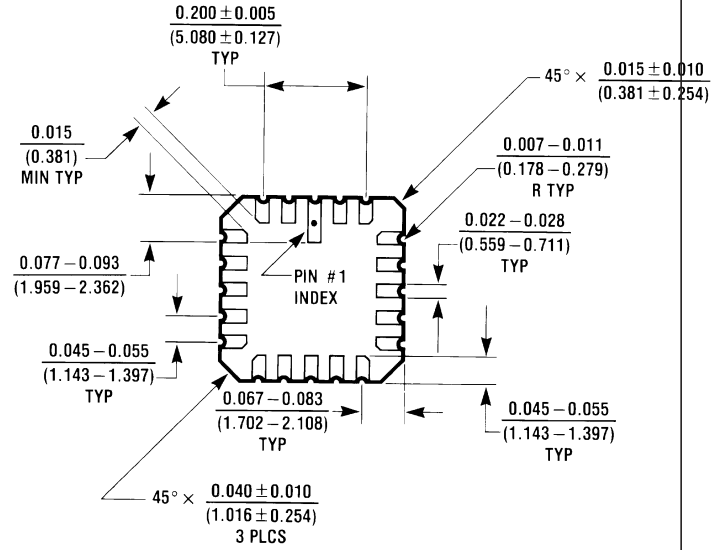
Physical Dimensions inches (millimeters) unless otherwise noted



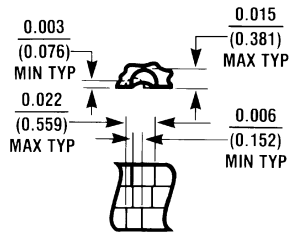
Top View



Side View



Bottom View

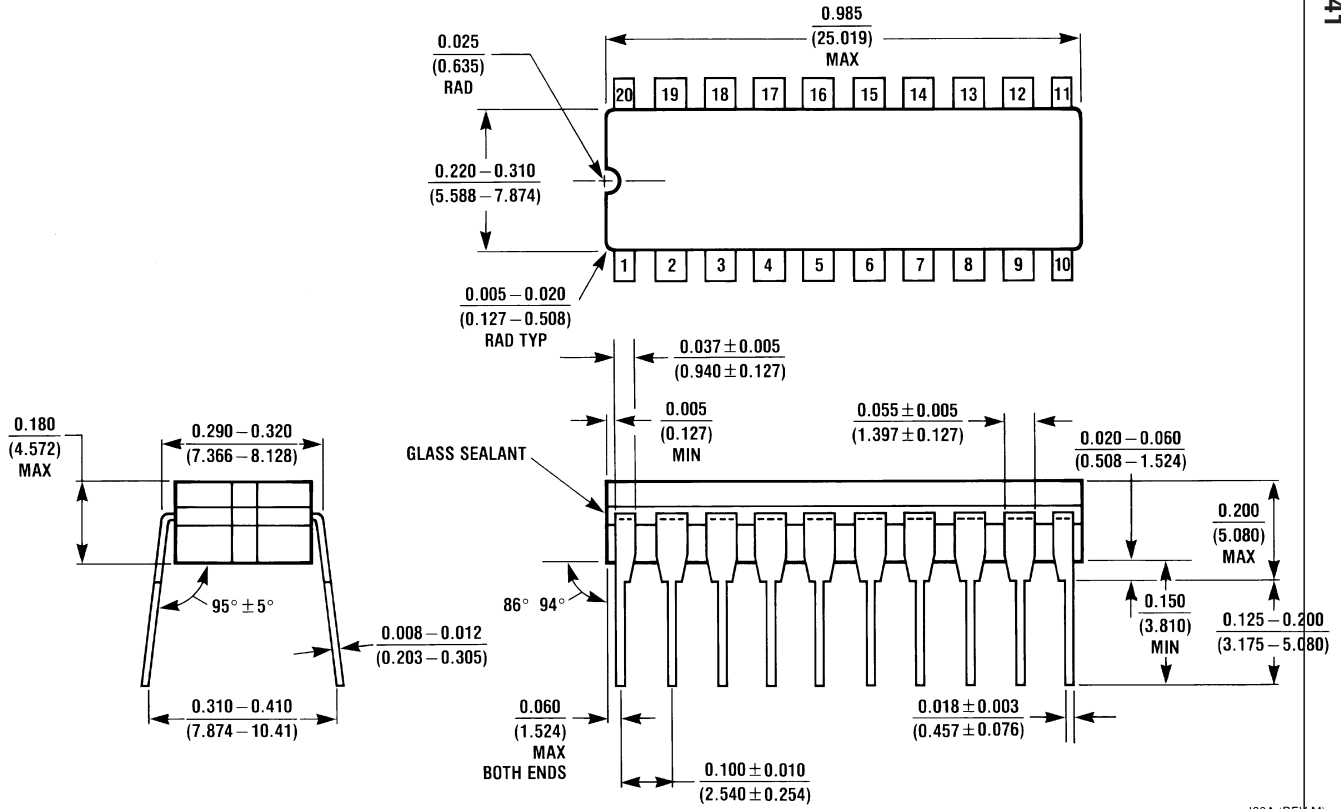


Detail A

**20-Lead Ceramic Leadless Chip Carrier
Package Number E20A**

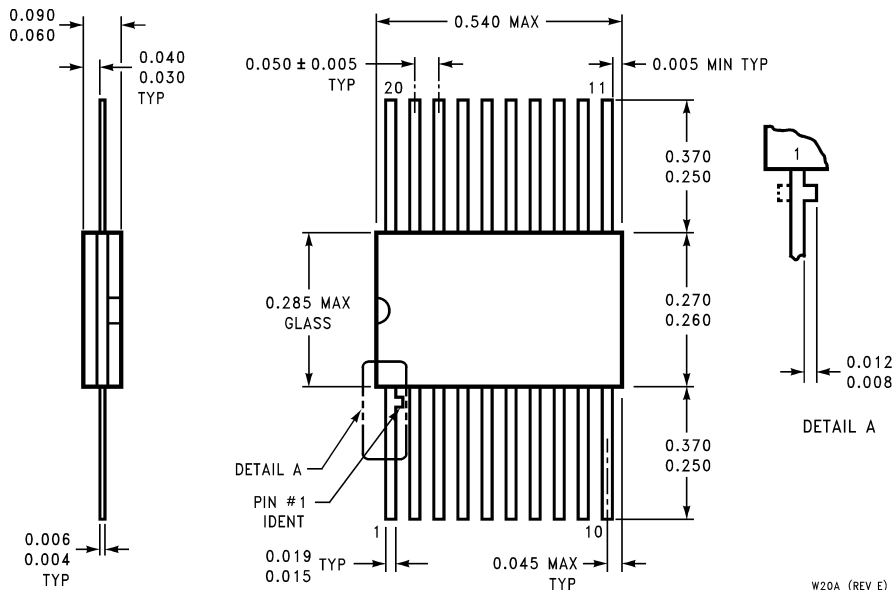
E20A (REV D)

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



J20A (REV M)

**20-Lead Ceramic Dual-In-Line
Package Number J20A**



W20A (REV E)

**20-Lead Ceramic Flatpack
Package Number W20A**

Notes

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